

Heterogeneous Packaging Technologies for Chiplet and Memory Integration

Yan Li, WooPoung Kim

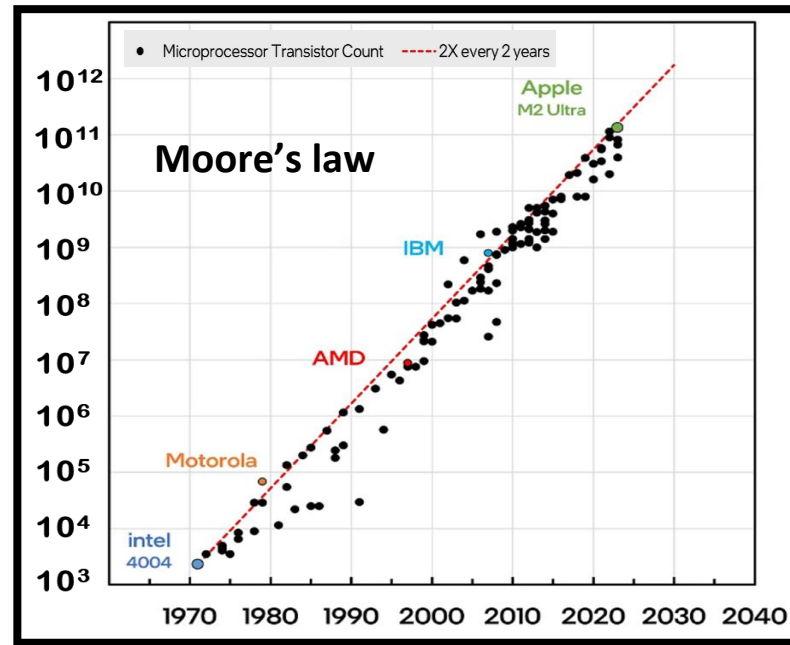
Samsung Semiconductor Inc. San Jose, USA

Outline

- **Introduction**
- **Chiplet based heterogeneous integration platform**
- **Innovative memory integration solutions**
- **Novel Integrated Stack Capacitors (ISC) integration**
- **Conclusion**

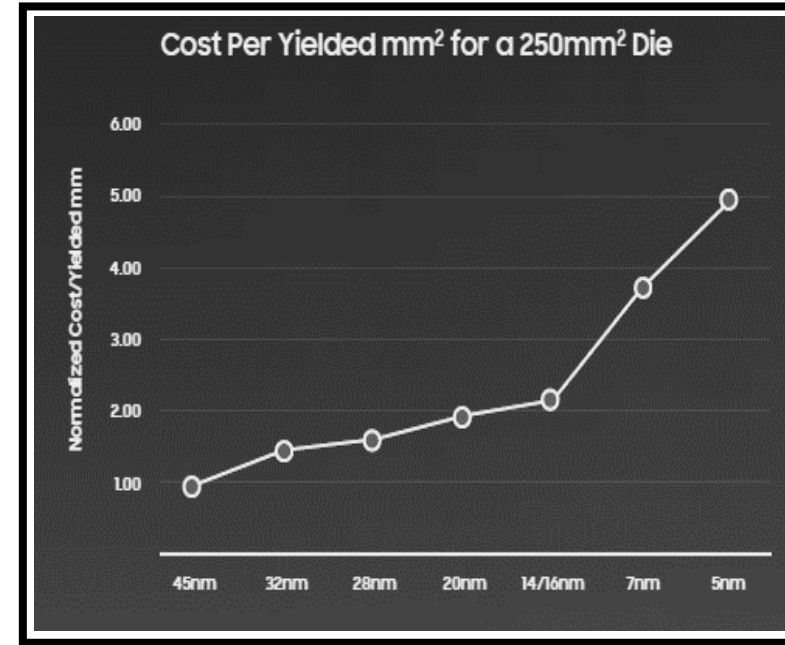
Introduction

Advanced Packaging techniques are utilized to meet the market needs



Moore's law predicts the exponential growth of ICs since 1970s---**Market needs**

<https://semiconductor.substack.com/p/the-relentless-pursuit-of-moores>



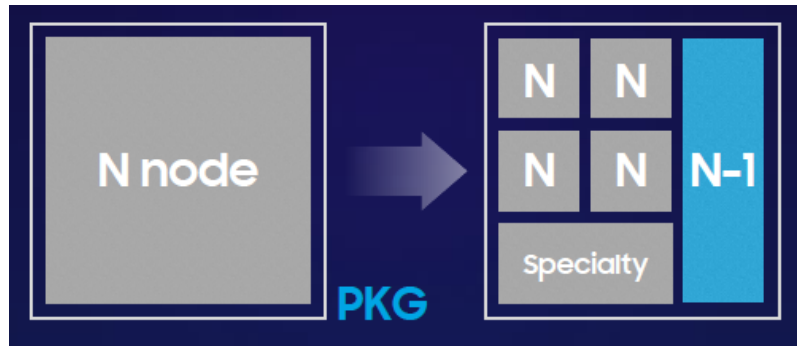
The exponential growth of cost per Yielded mm² for 250 mm² die ----**Challenges for Si level scaling and yielding**

Why Advanced Packaging?

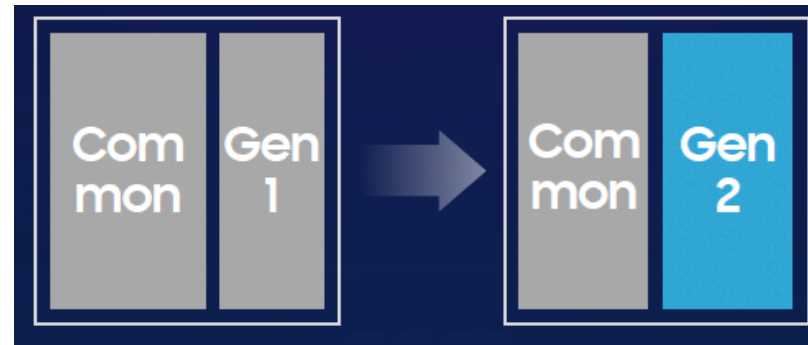
- Chiplet
- Heterogeneous integration
- Die stacking

Introduction

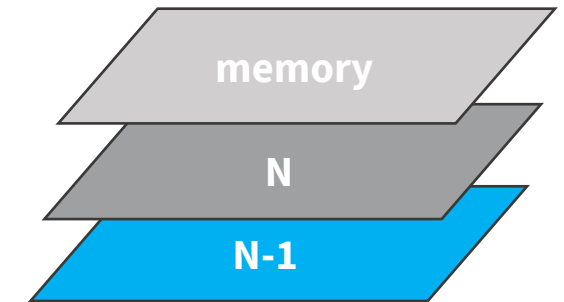
Chiplet; Heterogenous integration; die stacking



High yielding smaller chips and optimal process selection



Modular design, design reuse and mix & match



Die stacking footprint reduction

M. Kang, "Heterogeneous Integration Platform for Next Generation Computing" Sixth Annual Symposium on Heterogeneous Integration, February, 2023.

Introduction

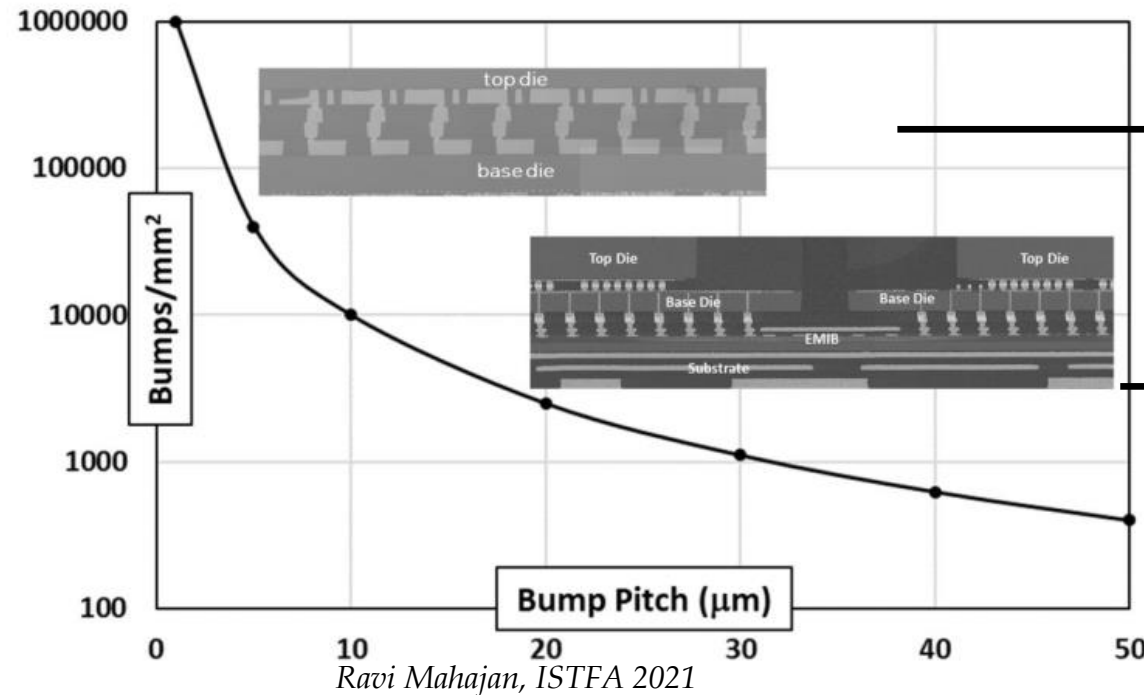
Technical and Logistic Challenges

- **Multi-domain co-design** involving both **power** and **signal** routing
- **Thermal management**
- **Facilitate Industry open platforms and standardizations** for high-speed and low power chiplet D2D communications: Universal Chiplet Interconnect Express (UCIe), Bunch of Wires (BoW), and High Bandwidth Interconnect (HBI) etc.
- **Establish and Clarify Agreements** on Si security and responsibilities in yield, Known Good Die (KGD), product or chiplet quality and reliability.

Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, “Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications”, OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

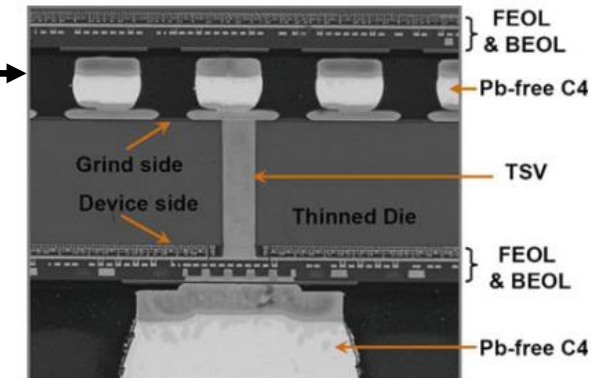
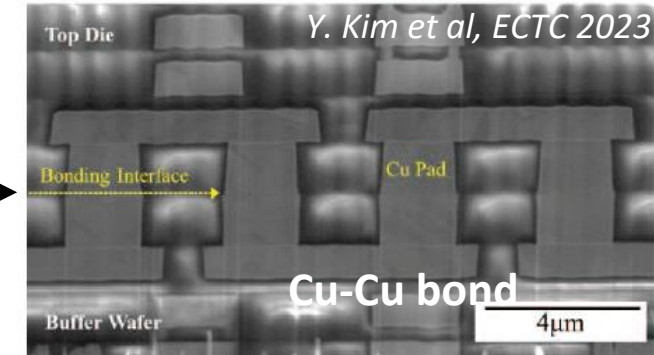
Introduction

Technical and Logistic Challenges



Hybrid Cu
Bonding
(HCB)

Thermal
Compressive
Bonding
(TCB)



Solder based

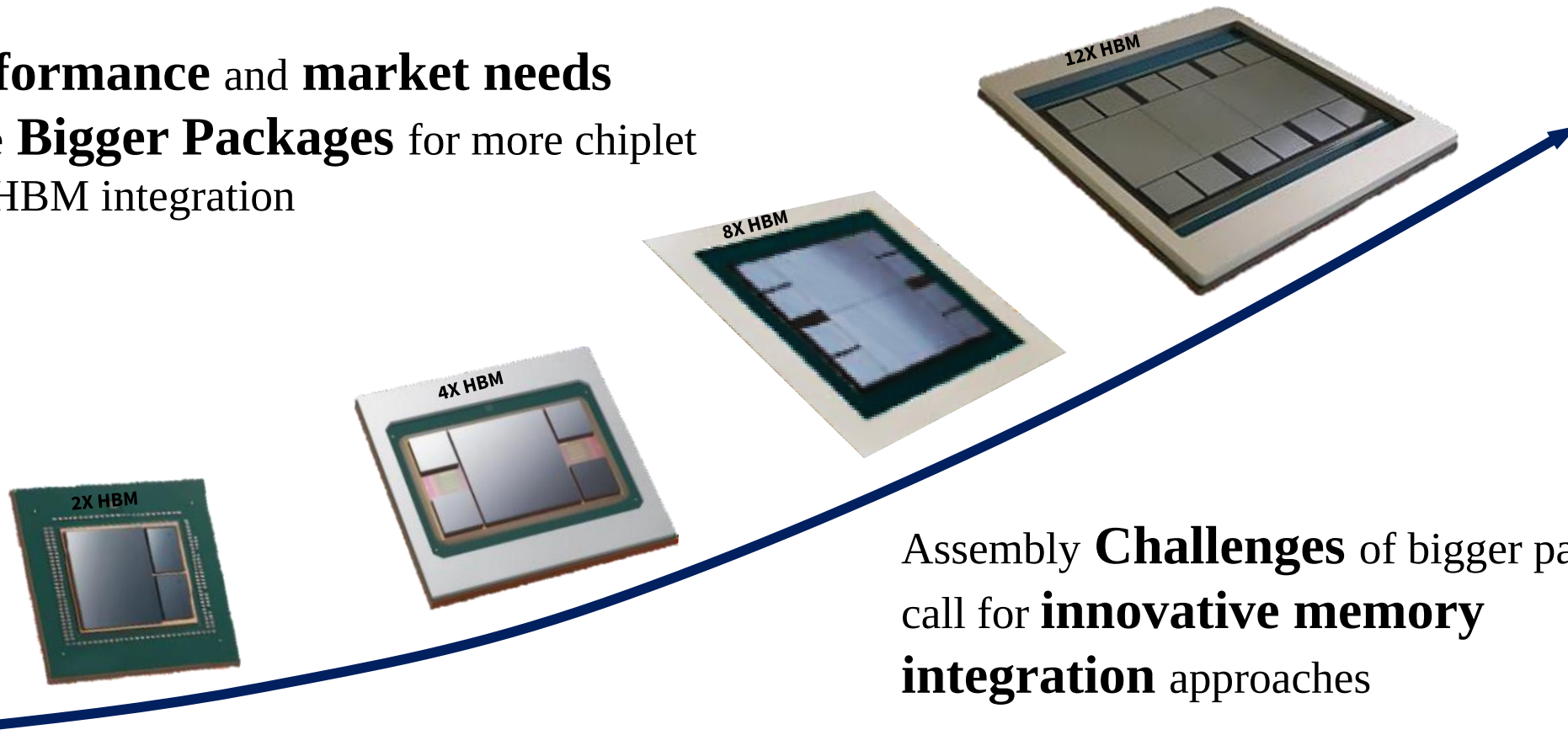
- D2D interconnect scaling down: HCB replacing TCB
 - Tighter bump pitch; smaller bumps
 - Gapless –thermal advantages

3D Microelectronic Packaging: From Architectures to Applications,
2nd edition, Springer, 2021, ISSN 1437-0387

Introduction

Technical and Logistic Challenges

Performance and **market needs**
drive **Bigger Packages** for more chiplet
and HBM integration

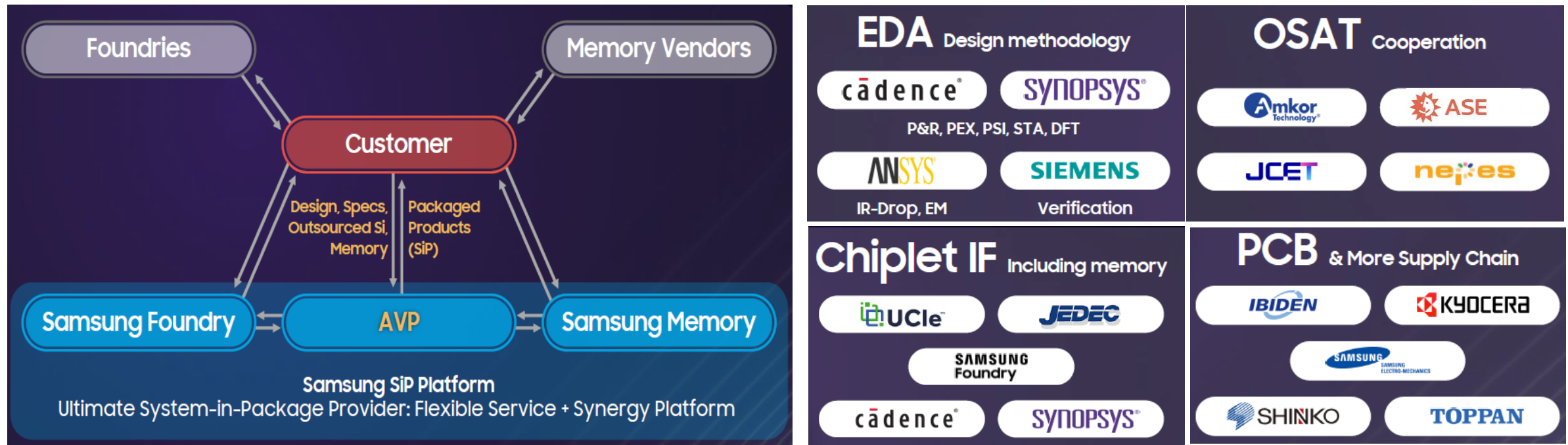


Assembly **Challenges** of bigger packages
call for **innovative memory
integration** approaches

Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, "Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications", OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

Chiplet Based Heterogeneous Integration Platform

End to End, Flexible, Synergy, Eco system



M. Kang, "Heterogeneous Integration Platform for Next Generation Computing" Sixth Annual Symposium on Heterogeneous Integration, February, 2023.

Chiplet Based Heterogeneous Integration Platform

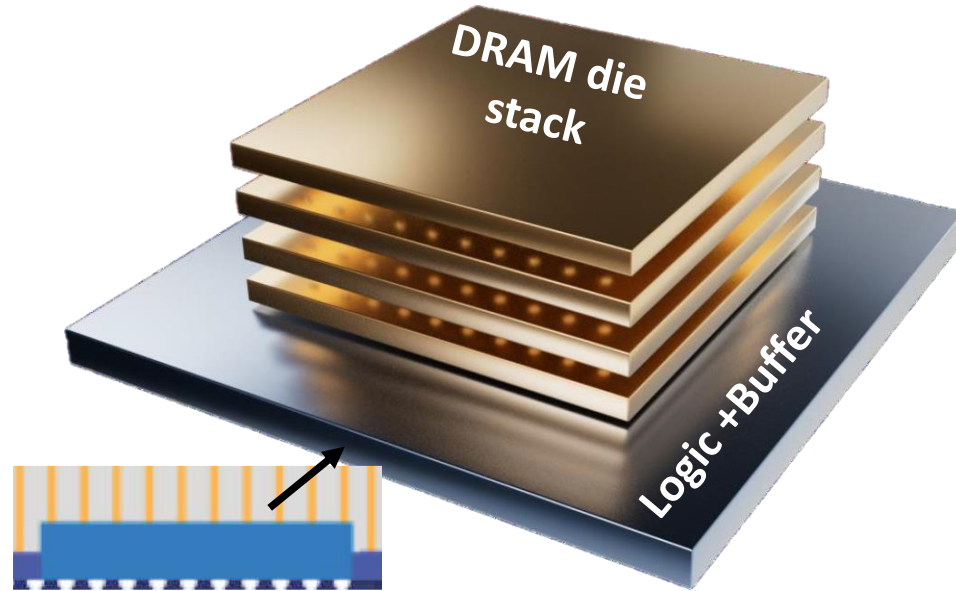
Type	Current offering	Roadmap	Pictures	Type	Current offering	Roadmap	Pictures
FOPLP	RDL L/S: 5 μ m; Bump pitch: 90 μ m; Pkg. thickness: 0.58mm	RDL L/S: 5 μ m; Bump pitch: 90 μ m; Pkg. thickness: 0.58mm		I-Cube E	Interposer size: 3x reticle; # of HBM: 8x; μ bump pitch: 40 μ m; Interposer C4 pitch: 150 μ m; Package size: 85 $\times$ 85mm ²	Interposer size: 4+ reticle; # of HBM: 12x; μ bump pitch: 25 μ m; Interposer C4 pitch: 125 μ m; Package size: 100 $\times$ 100mm ²	
FOWLP	RDL L/S: 2 μ m; Bump pitch: 90 μ m; Pkg. thickness: 0.35mm	RDL L/S: 1 μ m; Bump pitch: $\leq$ 75 μ m; Pkg. thickness: 0.33mm		X-Cube (TCB)	Bump pitch: 25 μ m; Silicon thickness: 40 μ m	Bump pitch: $\leq$ 21 μ m; Silicon thickness: <40 μ m	
I-Cube S	Interposer size: 3x reticle; # of HBM: 8x; μ bump pitch: 40 μ m; Interposer C4 pitch: 150 μ m; Package size: 85 $\times$ 85mm ²	Interposer size: 4+ reticle; # of HBM: 12x; μ bump pitch: 25 μ m; Interposer C4 pitch: 125 μ m; Package size: 100 $\times$ 100mm ²		X-Cube (HCB)	Bump pitch: 4 μ m; Silicon thickness: 10 μ m	Bump pitch: $\leq$ 3 μ m; Silicon thickness: <10 μ m	

M. Kang, "Heterogeneous Integration Platform for Next Generation Computing" Sixth Annual Symposium on Heterogeneous Integration, February, 2023.

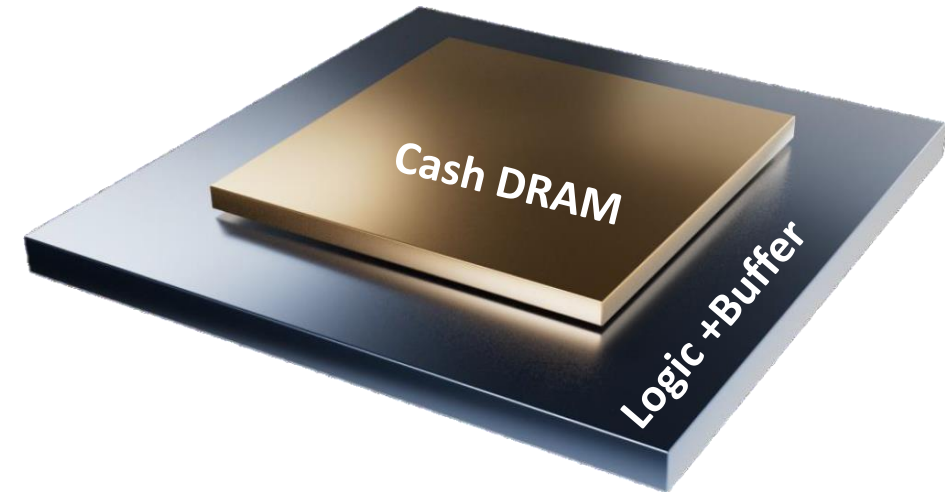
Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, "Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications", OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

Innovative Memory Integration Solutions

3D Memory Integration



3D custom HBM



3D Cash Memory

Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, "Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications", OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

Innovative Memory Integration Solutions

3D Custom HBM

		2023	2024	2025~	
HBM Product		HBM3	HBM3E	HBM4	
Architecture	HBM Thickness	720um	720um	775um	
	Stack #	8/12H	8/12H	12/16H	
	Structure	8H-Stack	12H-Stack	16H-Stack	Custom HBM
Tech.	Joint Gap	TCB	9um/7.3um	7.3um	<7.0um
		HCB			
			Gapless		

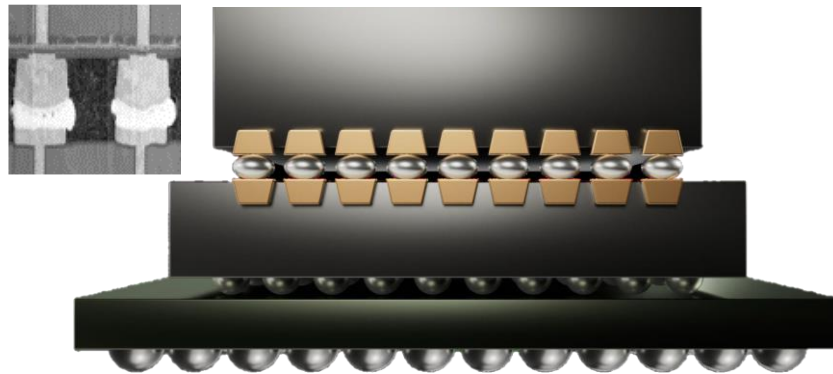
W. Kim, "Advanced Packaging in the Era of HPC and AI" Seventh Annual Symposium on Heterogeneous Integration, February, 2024.

Innovative Memory Integration Solutions

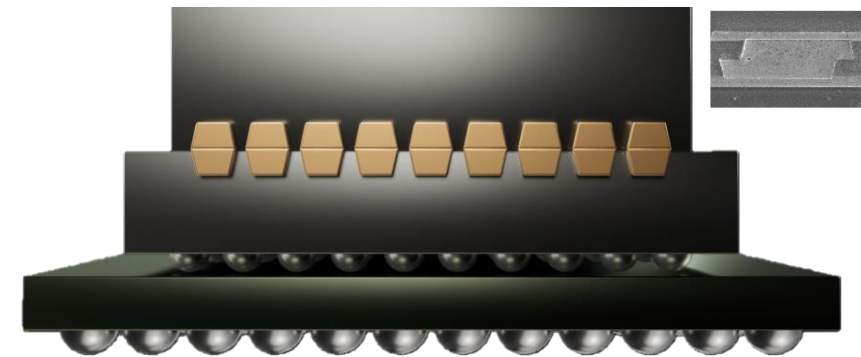
HCB replacing TCB in 3D die stacking

Cu-Cu replacing solder based micro bumps

- $\sim \times 100$ denser interconnects
- Up to $\times 150$ more bandwidth
- Up to 30% more allowable power



Solder based micro bump by TCB
>20 μ m in bump size and pitch

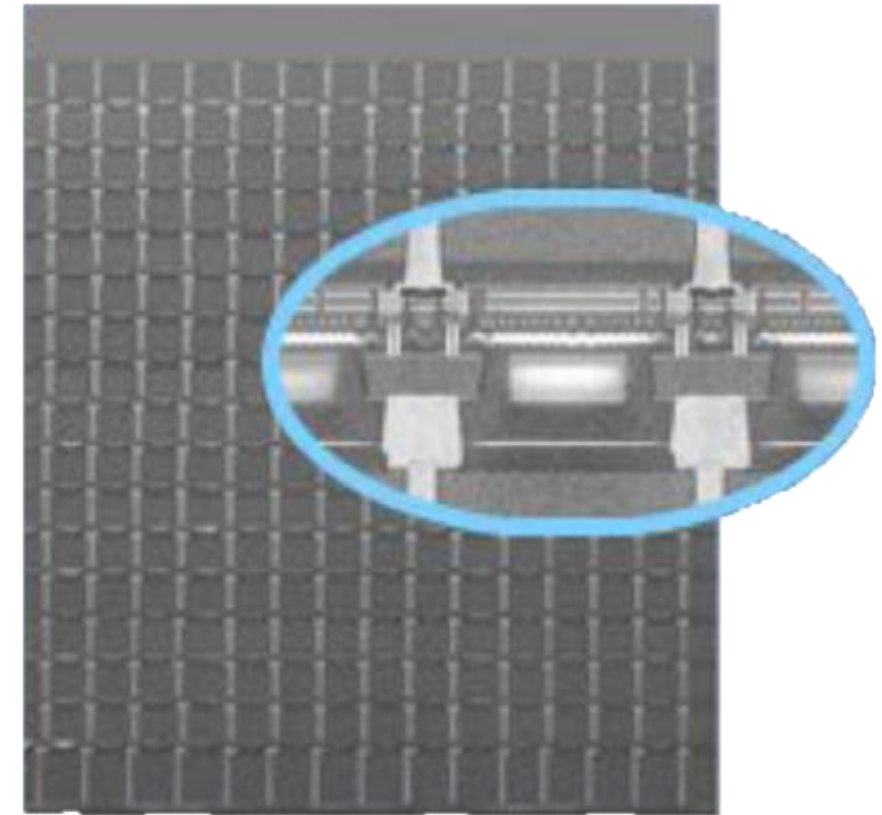
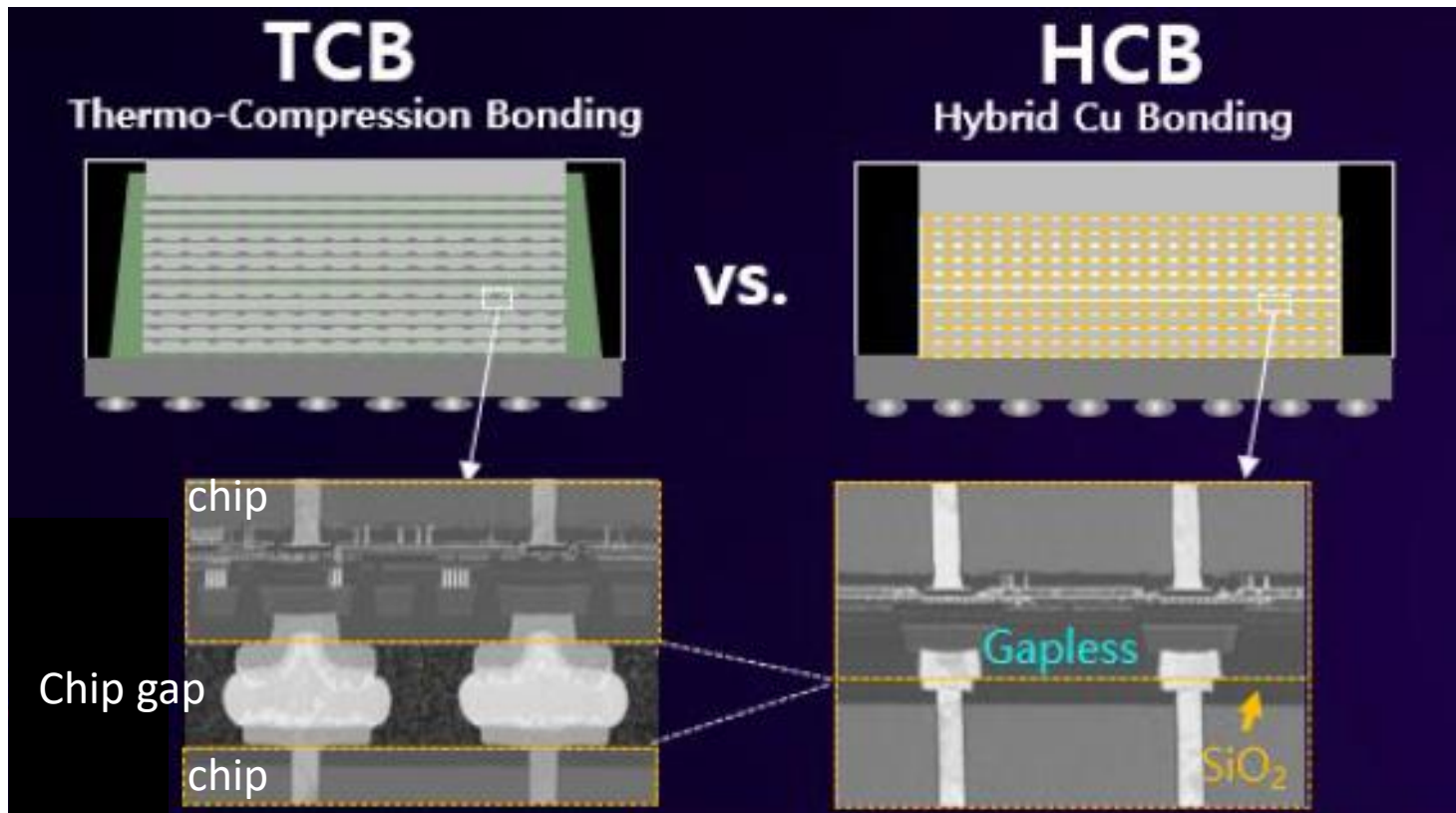


Cu-Cu by HCB
A few μ m in bump size and pitch

Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, "Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications", OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

Innovative Memory Integration Solutions

HCB replacing TCB in HBM



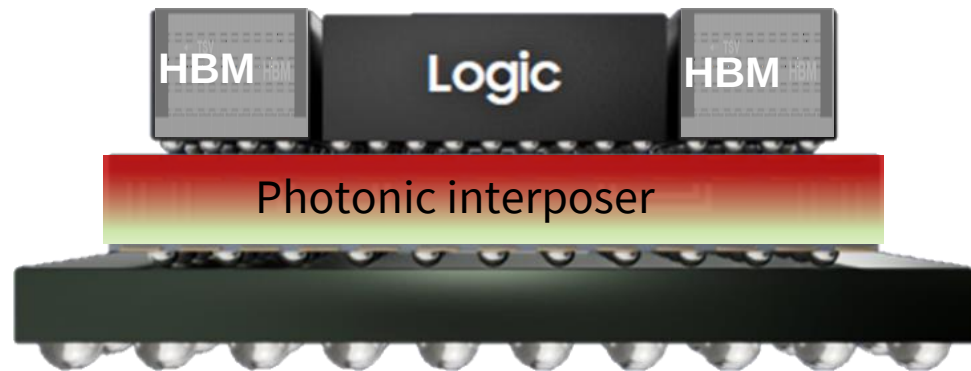
16H HBM by HCB

W. Kim, "Advanced Packaging in the Era of HPC and AI" Seventh Annual Symposium on Heterogeneous Integration, February, 2024.

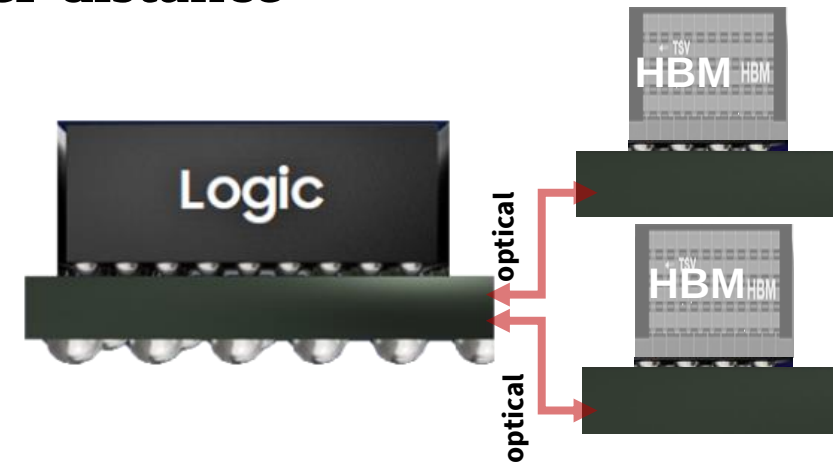
Innovative Memory Integration Solutions

Optical Interconnects could be a promising approach

- Exceptionally high bandwidth densities
- Ultra low power consumption per bit or per distance



Development trend: Optical interface between HBM and Logic



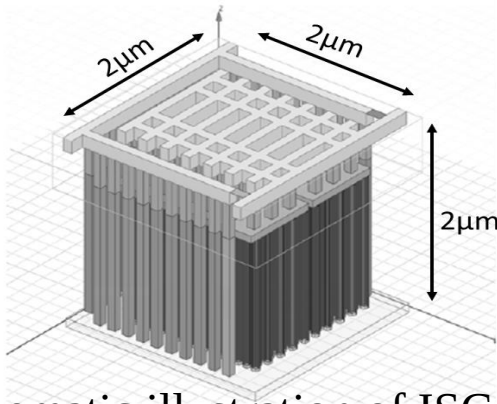
Development trend: Optical connection between logic and HBM packages

M. Tan, et al “Co-packaged optics (CPO): status, challenges, and solutions”, Frontiers of Optoelectronics”, 16:1, 2023

N. Pleros et al “Optical Interconnect and Memory Technologies for Next Generation Computing”, 2016 18th International Conference on Transparent Optical Networks (ICTON), Trento, Italy, 2016, pp. 1-4, doi: 10.1109/ICTON.2016.7550267.

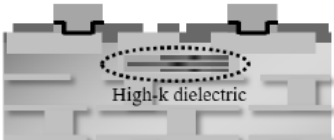
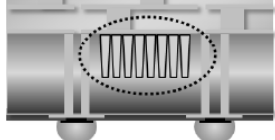
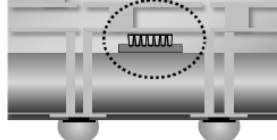
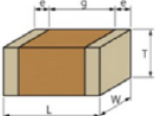
Y. Li, J. Yang, K. Chatterjee, P. Asrar, S. Jeong, and W. Kim, “Advanced package technologies for chiplet adoption and memory integration in HPC/AI applications”, OCP global summit, Future Technologies symposium, October 18, 2023, San Jose.

Novel Integrated Stack Capacitors (ISC) integration

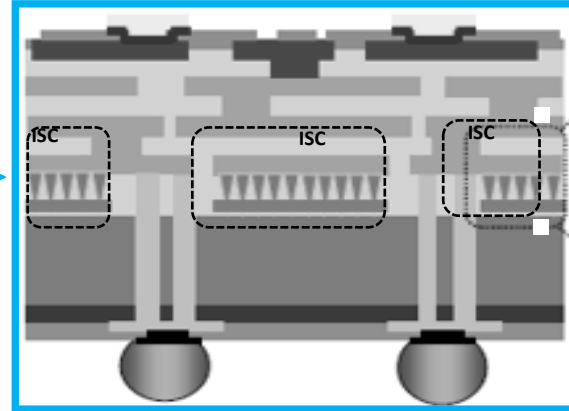
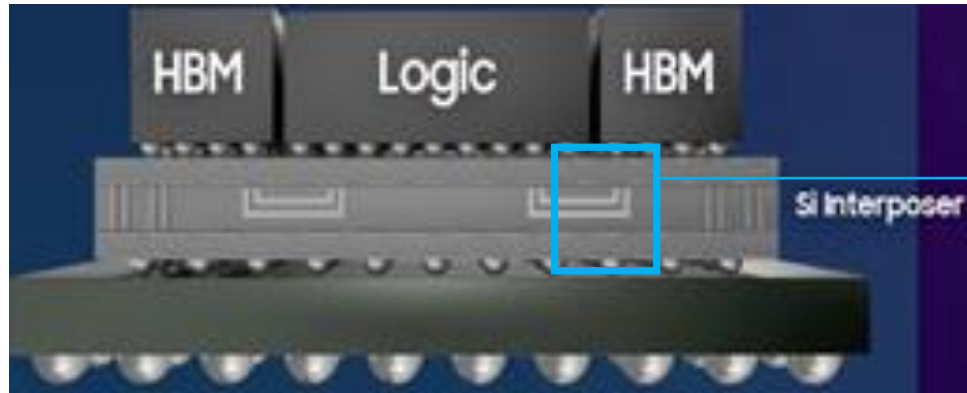


Schematic illustration of ISC with a silicon area of $2 \times 2 \mu\text{m}^2$

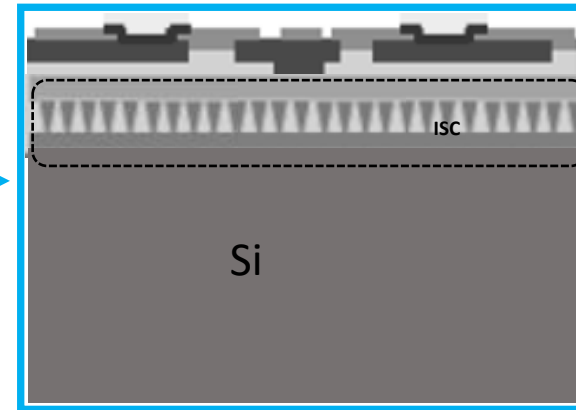
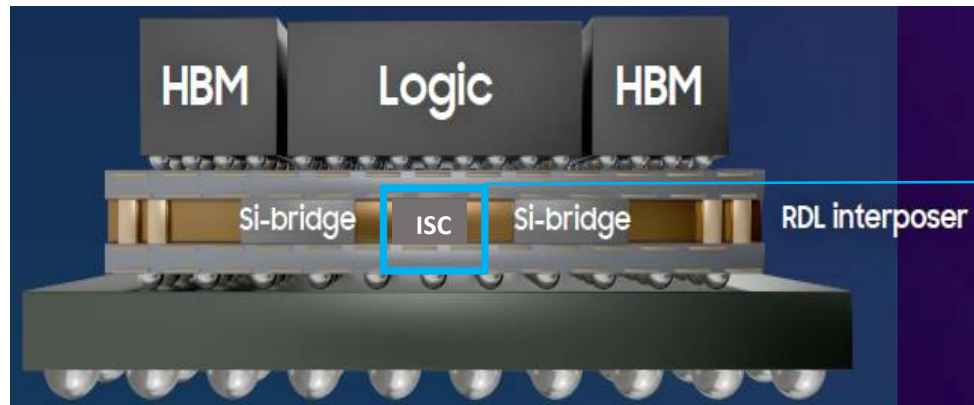
- High Power demands in HPC
- Low impedance Power Distribution Network (PDN)
- Capacitors with small form factors, high capacitance density, stable at high T.

	Metal-Insulator-Metal (MIM)	Deep Trench Capacitor (DTC)	Integrated Stack Capacitors (ISC)	Multilayer Ceramic Capacitor (MLCC)
				
Cap. density	× 1.0	× 7.5	× 7.5	× 75
Cap. Height	≤ 2 μm	~ 30 μm	~ 2 μm	~ 1 mm
Cap. density change with T?	No	No	No	Drop at high T

Novel Integrated Stack Capacitors (ISC) integration

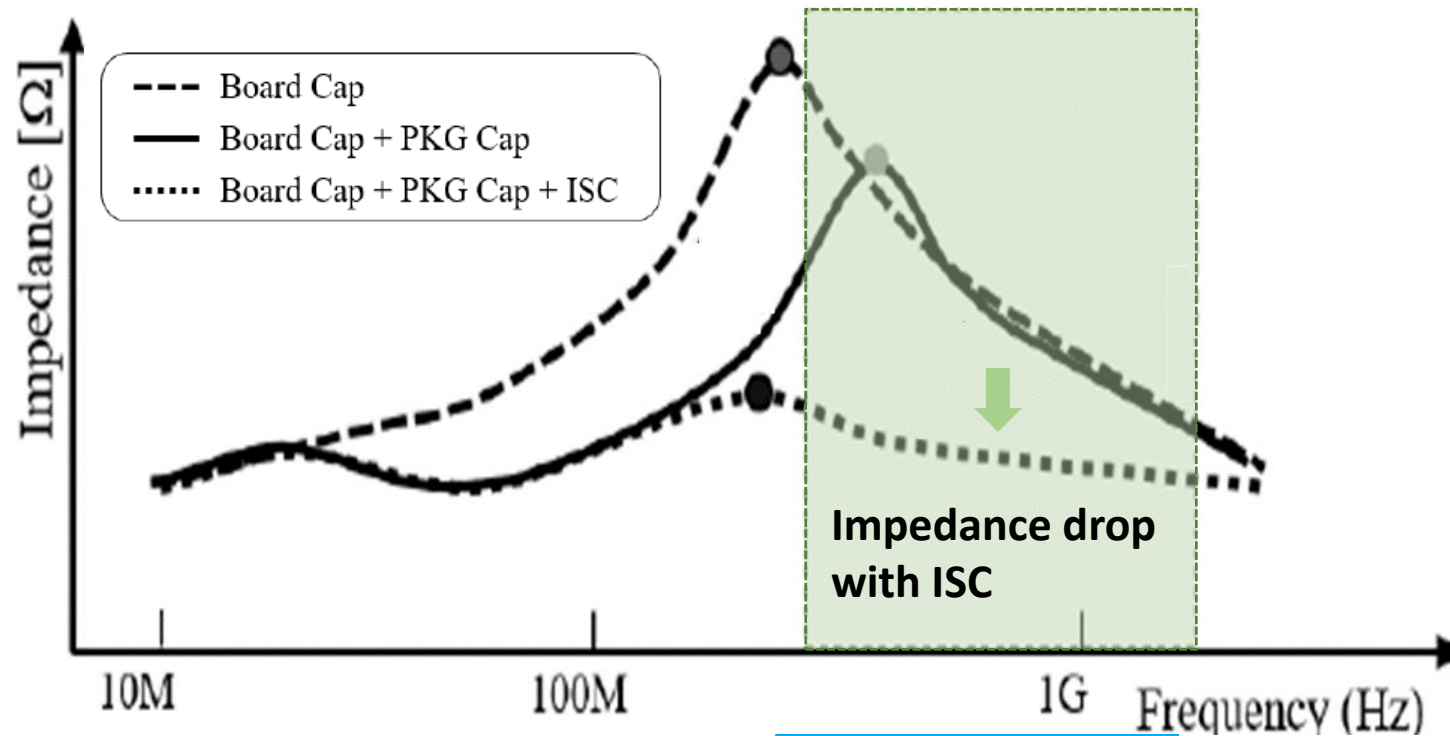


ISC is embedded between metal layers in a Si interposer



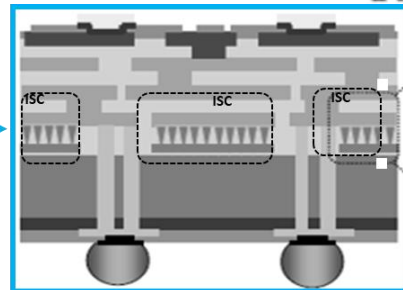
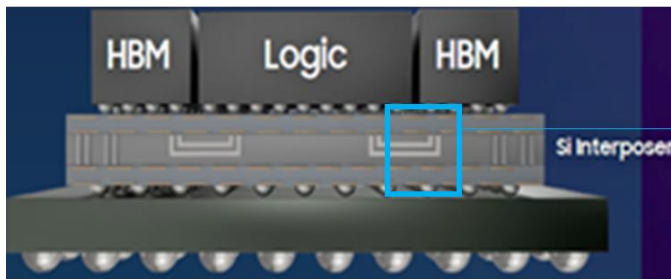
ISC die is embedded inside a RDL interposer along with the bridge dies

Novel Integrated Stack Capacitors (ISC) integration



Modeling showing significant impedance drop at high frequency range by adding ISC to Si interposer

E. Song, D. et al, "Power Integrity performance Gain of a Novel Integrated Stack Capacitor (ISC) Solution for High-end Computing Applications", IEEE 70th Electronic Components and Technology Conference (ECTC), 2020, pp. 1358-1362.



	Current		
ISC Cap density (nF/mm ²)	1,350 1	2,200 2	2,750

M. Kang, "Heterogeneous Integration Platform for Next Generation Computing" Sixth Annual Symposium on Heterogeneous Integration, February, 2023.

Conclusion

- **The one-stop advanced package solution for HPC and AI applications**
- **Innovative memory integration solutions**
- **The novel adoptions of ISC into the chiplet based heterogeneous integration platform**